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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
10/614,604 07/07/2003		Naomi M. Jenkins	2000.107500/TT5487	7792		
23720	7590 01/13/2006	EXAMINER				
	MORGAN & AMERSO OND, SUITE 1100	VO, HIEN XUAN				
HOUSTON, 7	•	ART UNIT	PAPER NUMBER			
			2863			
			DATE MAIL ED: 01/12/2006	DATE MAIL ED: 01/12/2006		

Please find below and/or attached an Office communication concerning this application or proceeding.

		Applicat	on No.	Applicant(s)				
		10/614,6	04	JENKINS ET AL.	(m)			
Office Action Summary		Examine	r	Art Unit				
		Hien X. V	o'	2863				
David fo	The MAILING DATE of this commu	nication appears on th	e cover sheet with the c	orrespondence addr	ress			
WHIC - Exte after - If NC - Failu Any	ORTENED STATUTORY PERIOD FOR CHEVER IS LONGER, FROM THE MINISTRY PROVIDED FOR THE MINISTRY PROVI	MAILING DATE OF T s of 37 CFR 1.136(a). In no er munication. tatutory period will apply and v y will, by statute, cause the ap	HIS COMMUNICATION /ent, however, may a reply be tim vill expire SIX (6) MONTHS from plication to become ABANDONE	N. nely filed the mailing date of this com D (35 U.S.C. § 133).	,			
Status								
1) 又	Responsive to communication(s) fil	ed on <i>07 July 2003</i> .						
		2b)⊠ This action is i	non-final.					
3)								
,	closed in accordance with the pract							
Disposit	ion of Claims		·					
4)⊠	4) Claim(s) <u>1-50</u> is/are pending in the application.							
	4a) Of the above claim(s) is/are withdrawn from consideration.							
5)	Claim(s) is/are allowed.							
6)⊠	Claim(s) 1-3,6-8,13,14,16-18,22,23	<u>,26,27,31-33,38,39,4</u>	2-44,46 and 49 is/are re	ejected.				
7)🖂	Claim(s) 4,5,9-12,15,19-21,24,25,2	8,29,34-37,40,41,45,	<u>47,48 and 50</u> is/are obj	ected to.				
8)[Claim(s) are subject to restri	ction and/or election	requirement.	•				
Applicat	ion Papers							
9)[The specification is objected to by the	ne Examiner.						
10)⊠	The drawing(s) filed on 07 July 2003	<u>3</u> is/are: a)⊠ accepte	ed or b) Objected to be	by the Examiner.				
	Applicant may not request that any object	ection to the drawing(s)	be held in abeyance. See	e 37 CFR 1.85(a).				
	Replacement drawing sheet(s) including							
11)	The oath or declaration is objected	to by the Examiner. N	ote the attached Office	Action or form PTC)-152.			
Priority (under 35 U.S.C. § 119							
,	Acknowledgment is made of a claim All b) Some * c) None of:)-(d) or (f).				
	1. Certified copies of the priority							
	2. Certified copies of the priority							
	3. Copies of the certified copies			ed in this National S	tage			
* (application from the Internati See the attached detailed Office acti	•	• • • •	ad				
`	See the attached detailed Office acti	on for a list of the cer	anda dopies not receive	м.				
Attachmer	, ,		A) D Jatanian Comme	(PTO 412)				
	ce of References Cited (PTO-892) ce of Draftsperson's Patent Drawing Review (PTO-948)	4) Interview Summary Paper No(s)/Mail Da					
3) 🔲 Infor	mation Disclosure Statement(s) (PTO-1449 o		5) Notice of Informal P		152)			
Раре	er No(s)/Mail Date		6)					

Application/Control Number: 10/614,604

Art Unit: 2863

DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 1. Claims 1-3, 6-8, 13-14, 16-18, 22-23, 26-27, 31-33, 38-39, 42-44, 46, 49 rejected under 35 U.S.C. 102(e) as being anticipated by Stoddard et al. (U.S. patent No. 6,587,744).

With respect to claims 1, 13, 16, 38, 44, Stoddard et al. disclose the automated run-to-run controller for controlling manufacturing processes including performing a process step upon a batch of workpieces using a processing tool (see e.g. col. 1, lines 15-19 and 30-32); performing a tool state analysis upon said processing tool (see e.g. col. 5, lines 20-35); and performing a dynamic metrology routing adjustment process based upon said tool state analysis (see e.g. Fig.2 and col. 5, lines 1-39), said dynamic metrology routing adjustment process comprising correlating the tool state analysis to the batch of workpieces and adjusting a metrology routing based upon said correlation (see e.g. col. 5, lines 40-67).

With respect to claims 2-3, 14, 18, 23, 39, 43, Stooddard et al. disclose the invention as claimed including the process step upon the batch of workpieces further comprises performing said process step upon a batch of semiconductor wafers (see e.g. col. 1, lines 20-23), the tool state analysis upon said processing tool further comprises acquiring tool state data (see e.g. col. 5, lines 20-40).

With respect to claims 6-8, Stoddard et al. disclose the invention as claimed including a fault detection analysis relating to said processing of said batch and determining at least one fault relating to an operation performed by said processing tool (see e.g. col. 4, lines 40-49).

With respect to claims 17, 22, 42, disclose the invention as claimed including a processing tool to process a batch of workpieces (see e.g. col. 1, lines 20-25); and a process controller operatively coupled to perform a tool state analysis upon said processing tool and to perform a dynamic metrology routing adjustment process based upon said tool state analysis, said dynamic metrology routing adjustment process comprising correlating said tool state analysis to said batch of workpieces and adjusting a metrology routing based upon said correlation (see e.g. col. 2, lines 20-35).

Claims 26-27, 46, 49 are method claims corresponding to apparatus claims 1, 13, 16. Therefore, claims 26-27, 46, 49 are rejected for the same rationales set forth for claims 1, 13, 16.

2. Claims 4-5, 9-12, 15, 19-21, 24-25, 28-29, 34-37, 40-41, 45, 47-48, 50 objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in

independent form including all of the limitations of the base claim and any intervening claims.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Hien X. Vo whose telephone number is (571) 272-2282. The examiner can normally be reached on M-F (8:00-5:30) First Friday Off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Barlow can be reached on (571) 272-2269. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Hien Vo 01/07/06

John/Barlow
Supervisory/Patent Exeminer
Technology Center 2800